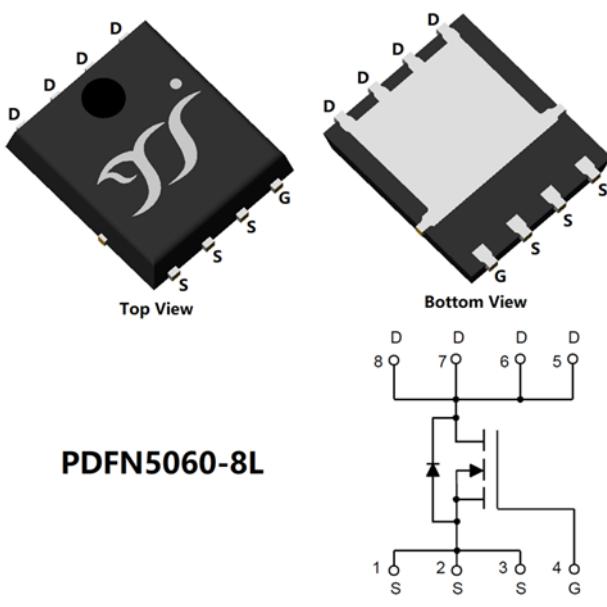


**N-Channel Enhancement Mode Field Effect Transistor****Product Summary**

- $V_{DS}$  30V
- $I_D$  50A
- $R_{DS(ON)}$  (at  $V_{GS} = 10V$ )  $< 6.0\text{mohm}$
- $R_{DS(ON)}$  (at  $V_{GS} = 4.5V$ )  $< 8.0\text{mohm}$
- 100% EAS Tested
- 100%  $\nabla V_{ds}$  Tested

**General Description**

- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$
- Moisture Sensitivity Level 1
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

**Applications**

- High current load applications
- Load switch
- Hard switched and high frequency circuits
- Uninterruptible power supply

**■ Absolute Maximum Ratings ( $T_A=25^\circ\text{C}$  unless otherwise noted)**

Parameter		Symbol	Limit	Unit
Drain-source Voltage		$V_{DS}$	30	V
Gate-source Voltage		$V_{GS}$	$\pm 20$	V
Drain Current	$T_c=25^\circ\text{C}$	$I_D$	50	A
	$T_c=100^\circ\text{C}$		32	
Pulsed Drain Current <sup>A</sup>		$I_{DM}$	190	A
Total Power Dissipation <sup>B</sup>	$T_c=25^\circ\text{C}$	$P_D$	45	W
	$T_c=100^\circ\text{C}$		18	
Total Power Dissipation @ $T_A=25^\circ\text{C}$ <sup>C</sup>		$P_D$	6.0	W
Single Pulse Avalanche Energy <sup>D</sup>		$E_{AS}$	98	mJ
Thermal Resistance Junction-to-Case		$R_{\theta JC}$	2.8	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction-to-Ambient		$R_{\theta JA}$	21	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55~+150	$^\circ\text{C}$

**■ Ordering Information (Example)**

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJG50N03B	F1	YJG50N03B	5000	10000	100000	13" reel



# YJG50N03B

**■ Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$			1	$\mu\text{A}$
Gate-Body Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}}= \pm 20\text{V}, V_{\text{DS}}=0\text{V}$			$\pm 100$	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}= V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1	1.5	2.5	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=20\text{A}$		3.9	6.0	$\text{m}\Omega$
		$V_{\text{GS}}= 4.5\text{V}, I_{\text{D}}=15\text{A}$		6.0	8.0	
Diode Forward Voltage	$V_{\text{SD}}$	$I_{\text{S}}=20\text{A}, V_{\text{GS}}=0\text{V}$		0.85	1.2	V
Maximum Body-Diode Continuous Current	$I_{\text{S}}$				80	A
Gate Resistance	$R_{\text{g}}$	$f = 1 \text{ MHz}$		2.3		$\Omega$
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$		2191		$\text{pF}$
Output Capacitance	$C_{\text{oss}}$			300		
Reverse Transfer Capacitance	$C_{\text{rss}}$			247		
<b>Switching Parameters</b>						
Total Gate Charge	$Q_{\text{g}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V}, I_{\text{D}}=20\text{A}$		46.3		$\text{nC}$
Gate-Source Charge	$Q_{\text{gs}}$			8.8		
Gate-Drain Charge	$Q_{\text{gd}}$			9.2		
Reverse Recovery Charge	$Q_{\text{rr}}$	$I_{\text{F}}=20\text{A}, dI/dt=100\text{A/us}$		1.6		$\text{ns}$
Reverse Recovery Time	$t_{\text{rr}}$			11		
Turn-on Delay Time	$t_{\text{D(on)}}$			11		
Turn-on Rise Time	$t_{\text{r}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DD}}=15\text{V}, R_{\text{L}}=0.75\Omega, R_{\text{GEN}}=3\Omega$		80		$\text{ns}$
Turn-off Delay Time	$t_{\text{D(off)}}$			39		
Turn-off fall Time	$t_{\text{f}}$			92		

- A. Pulse Test: Pulse Width  $\leq 300\text{us}$ , Duty cycle  $\leq 2\%$ .
- B. The power dissipation  $P_{\text{D}}$  is based on  $T_{\text{J(MAX)}}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. The value of  $R_{\theta\text{JA}}$  is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with  $T_{\text{A}}=25^\circ\text{C}$ .
- D.  $T_{\text{J}}=25^\circ\text{C}$ ,  $V_{\text{DD}}=25\text{V}$ ,  $V_{\text{G}}=10\text{V}$ ,  $L=1.0\text{mH}$ ,  $I_{\text{AS}}=14\text{A}$ .

## ■ Typical Performance Characteristics

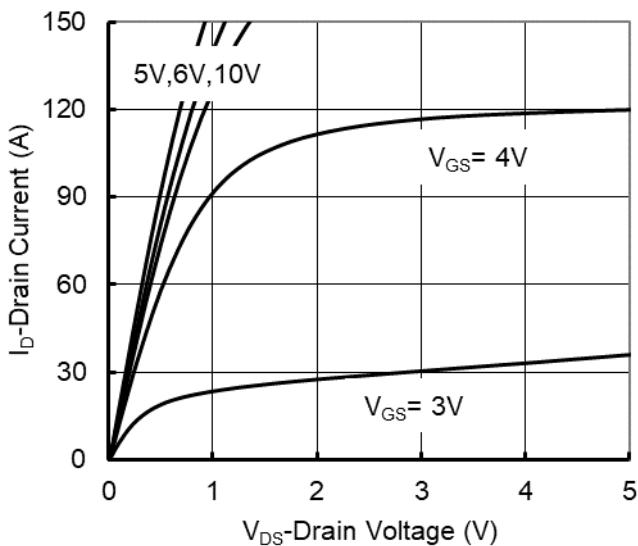


Figure 1. Output Characteristics

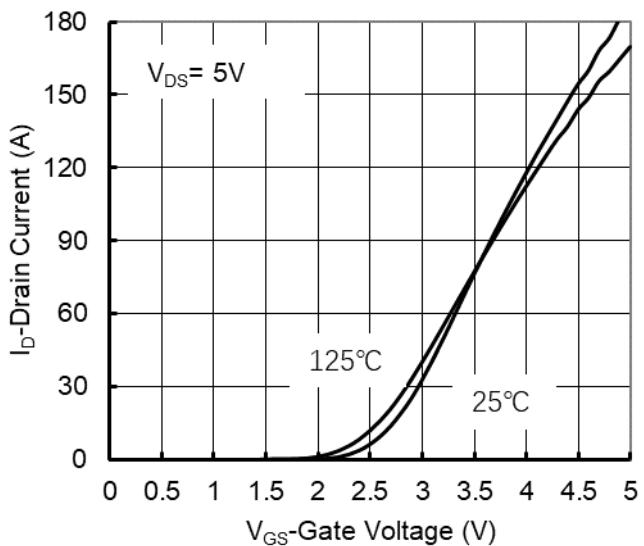


Figure 2. Transfer Characteristics

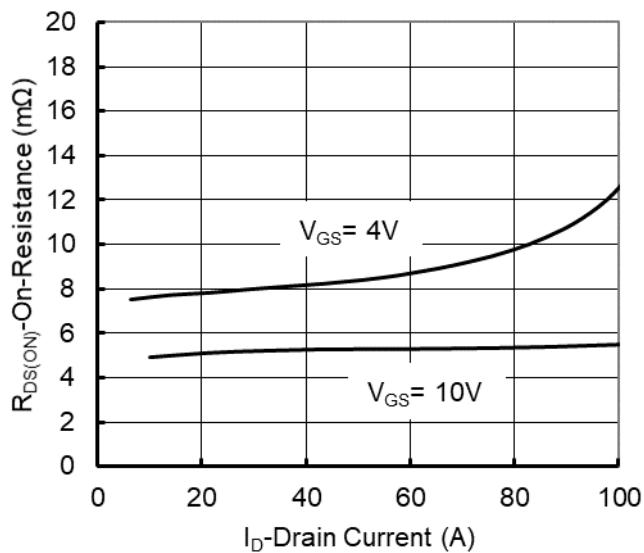


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

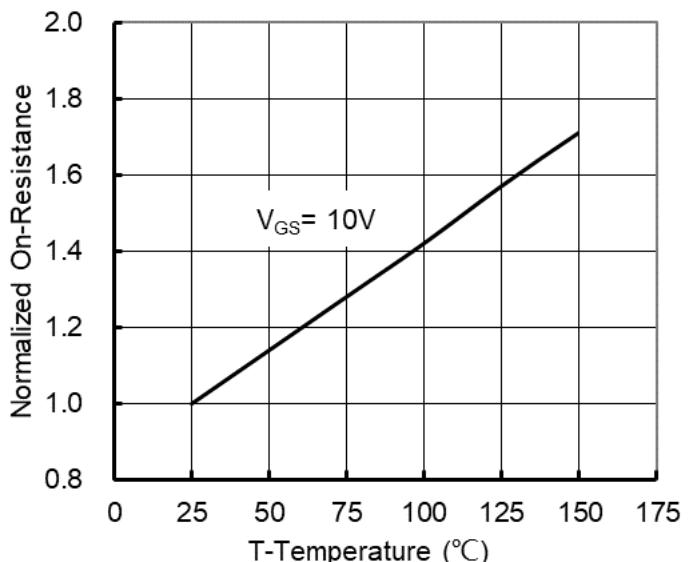


Figure 4. On-Resistance vs. Junction Temperature

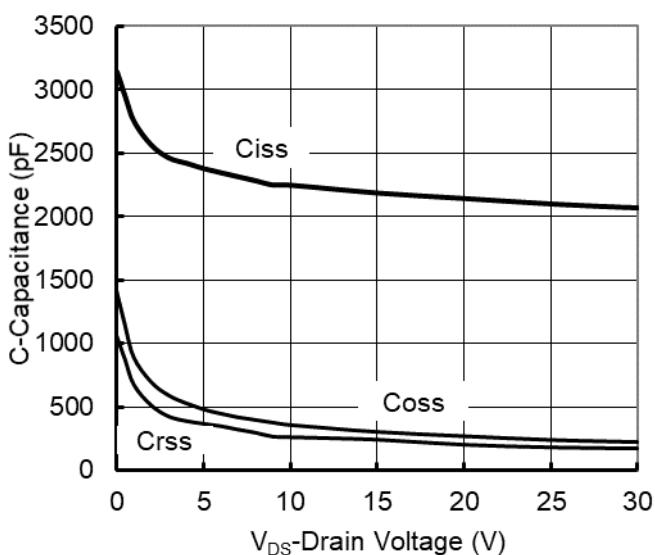


Figure 5. Capacitance Characteristics

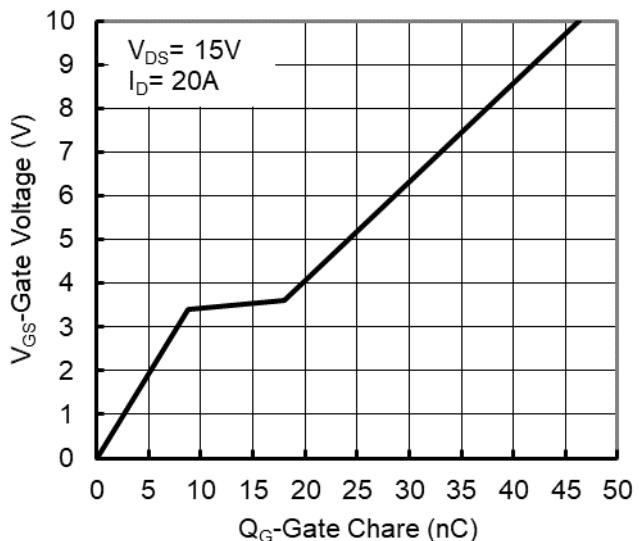


Figure 6. Gate Charge

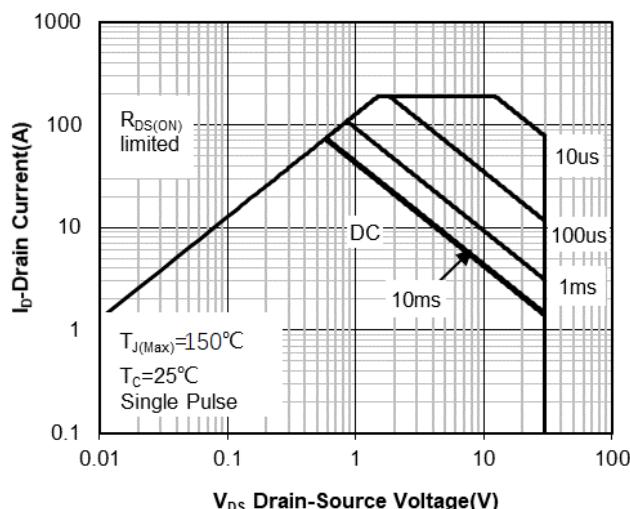


Figure 7. Safe Operation Area

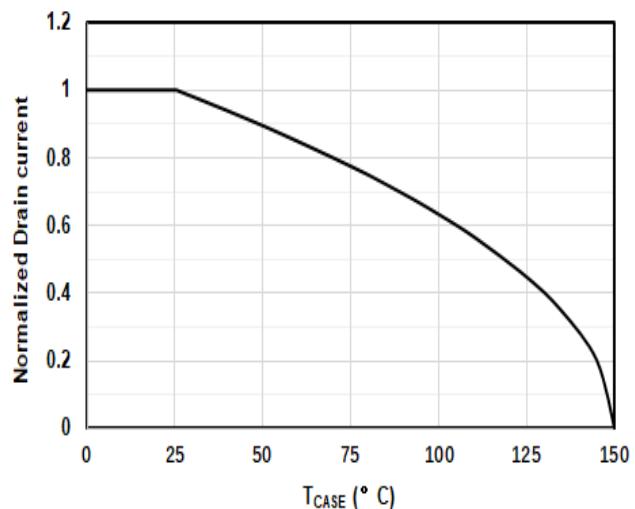


Figure 8. Maximum Continuous Drain Current vs Case Temperature

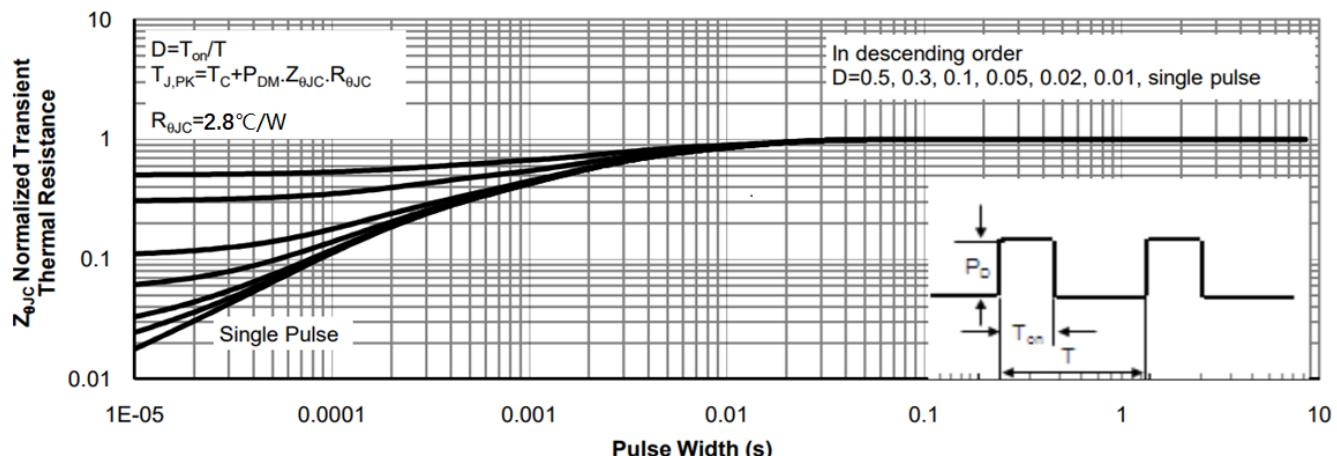
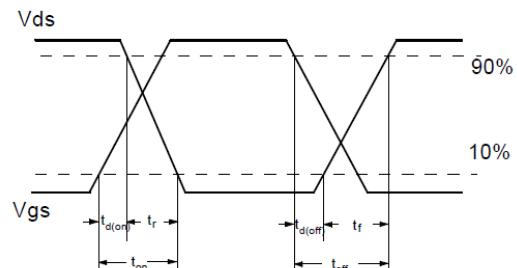
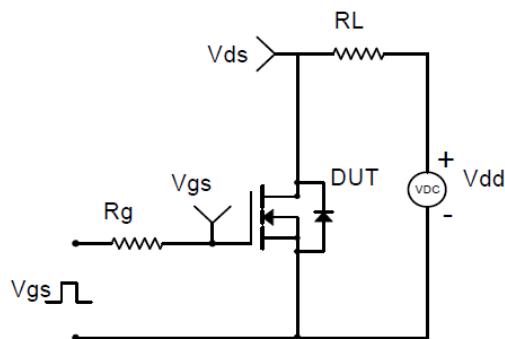
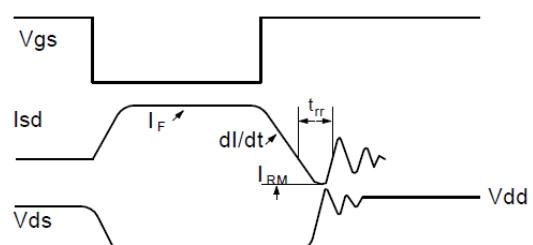
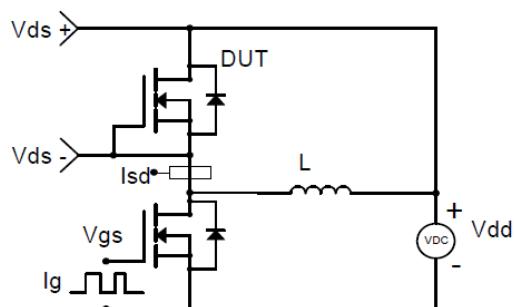


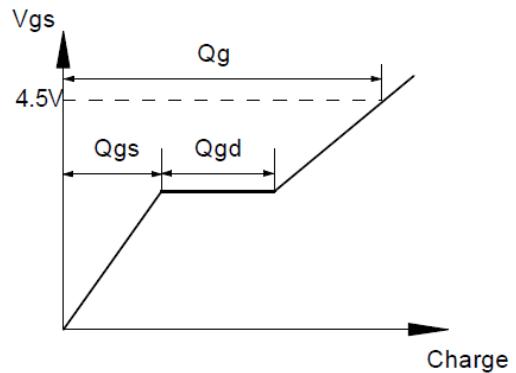
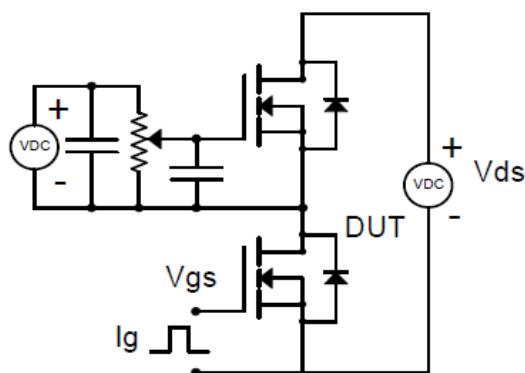
Figure 9. Normalized Maximum Transient Thermal Impedance



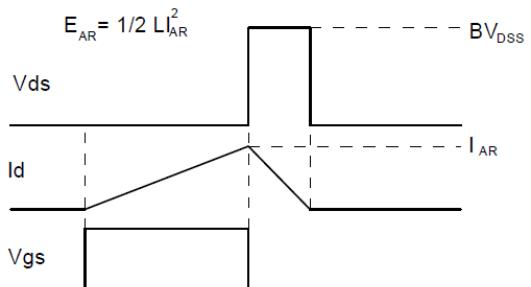
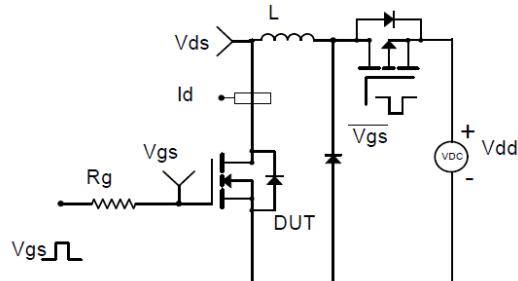
Resistive Switching Test Circuit &amp; Waveforms



Diode Recovery Test Circuit &amp; Waveforms



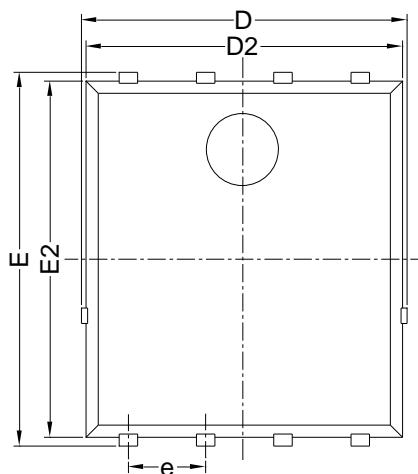
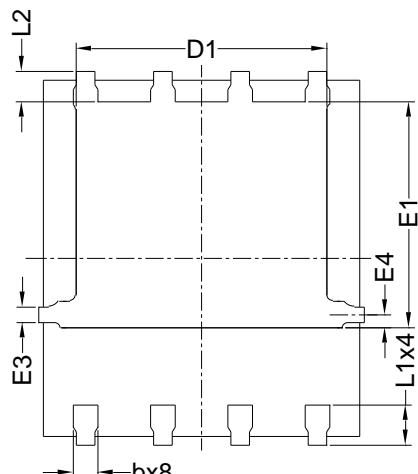
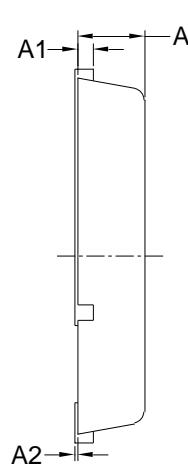
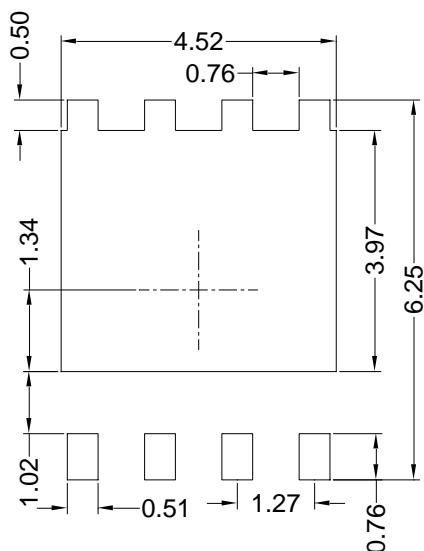
Gate Charge Test Circuit &amp; Waveform



Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms



## ■ PDFN5060-8L-B-1.1MM Package Information

Top View  
正面视图Bottom View  
背面视图Side View  
侧面视图Suggested Solder Pad Layout  
Top View

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	5.15	5.35	5.55
E	5.95	6.15	6.35
A	1.00	1.10	1.20
A1	0.254 BSC		
A2			0.10
D1	3.92	4.12	4.32
E1	3.52	3.72	3.92
D2	5.00	5.20	5.40
E2	5.66	5.86	6.06
E3	0.254 REF		
E4	0.21 REF		
L1	0.56	0.66	0.76
L2	0.50 BSC		
b	0.31	0.41	0.51
e	1.27 BSC		

## Note:

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.10\text{mm}$ .
3. The pad layout is for reference purposes only.



## Disclaimer

The information presented in this document is for reference only. Yangzhou Yangjie Electronic Technology Co., Ltd. reserves the right to make changes without notice for the specification of the products displayed herein to improve reliability, function or design or otherwise.

The product listed herein is designed to be used with ordinary electronic equipment or devices, and not designed to be used with equipment or devices which require high level of reliability and the malfunction of which would directly endanger human life (such as medical instruments, transportation equipment, aerospace machinery, nuclear-reactor controllers, fuel controllers and other safety devices), Yangjie or anyone on its behalf, assumes no responsibility or liability for any damages resulting from such improper use of sale.

This publication supersedes & replaces all information previously supplied. For additional information, please visit our website <http://www.21yangjie.com>, or consult your nearest Yangjie's sales office for further assistance.